

Notice of References Cited	Application/Control No. 10/034,070	Applicant(s)/Patent Under Reexamination KAISER ET AL.	
	Examiner John P Trimmings	Art Unit 2133	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,337,318	08-1994	Tsukakoshi et al.	714/708
	C	US-5,917,764	06-1999	Ohsawa et al.	365/200
	D	US-6,415,403	07-2002	Huang et al.	714/726
	E	US-6,085,334	07-2000	Giles et al.	714/7
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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	U	Dreibelbis et al., "Processor-Based Built-In Self-Test for Embedded DRAM", IEEE Journal of Solid State Circuits, Vol. 33 No. 11, November, 1998, pp1731-1740.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.